Contents STWBC-WA

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STWBC-WA

Contents

Description STWBC-WA

## 1 Description

The STWBC-WA is STMicroelectronics' wireless battery charger transmitter application optimized for wearable usage.

Thanks to its 5 V native supply, the STWBC-WA device is ideal to operate with USB power supplies.

Wireless battery charging systems replace the traditional power supply cable by means of electromagnetic induction between a transmitting pad or dongle (TX) and a battery-powered unit (RX), such as a smartwatch or sports gear.

The power transmitter unit is responsible for controlling the transmitting coil and generating the correct amount of power requested by the receiver unit. The receiver unit continuously provides the transmitter the correct power level requested, by modulating the transmitter carrier through controlled resistive or capacitive insertion. Generating the correct amount of power guarantees the highest level of end-to-end efficiency due to reduced energy waste. It also helps to maintain a lower operational temperature.

The digital wireless battery transmitter can adapt to the amount of energy transferred by the coil by modulating the frequency, duty cycles or coil input voltage.

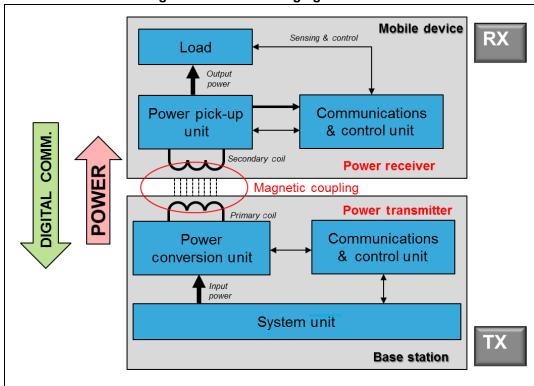


Figure 1. Wireless charging architecture

The STWBC-WA firmware sits on the top of the hardware to monitor and control the correct wireless charging operations.

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# 2 STWBC-WA system architecture

Figure 2 illustrates the overall system blocks implemented in the STWBC-WA architecture.

The STWBC-WA is a flexible controller which can be configured to support both half-bridge topologies for < 1 W power levels as well as full-bridge systems for driving < 3 W wearable devices. The integrated drivers require no external components between the STWBC-WA and the power MOSFETs application.

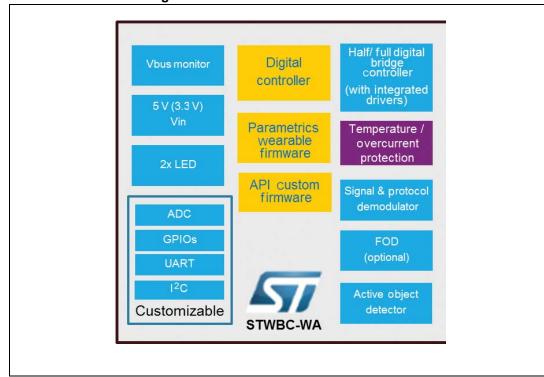


Figure 2. STWBC-WA device architecture

#### **Firmware**

The STWBC-WA firmware is available in two separate software packages:

- Turnkey: the firmware is distributed as a binary file.
- API customizable: the firmware is designed as a library, and external functions as well as peripherals can be added by means of APIs.

The STWBC-WA provides a set of APIs which allows the user to customize the application and tailor the system architecture to his needs. The UART and I<sup>2</sup>C communication interfaces, ADC and GPIOs can be controlled by the custom firmware via convenient APIs.

The software APIs allow a great deal of freedom to customize applications. The STWBC-WA device and the API library can be accessed by programming the internal controller via standard programming tools such as the IAR<sup>TM</sup> Workbench<sup>®</sup> Studio.



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# 3 STWBC-WA pinout and pin description

This section illustrates the pinout used by the STWBC-WA device.

DRIVEOUT[2] UART\_TX DIGIN[2] UART\_RX DRIVEOUT[1] PWM\_AUX/GPIO\_2 DIGIN[1] I2C\_SDA/DIGIN[4] DIGIN[0] 22 I2C\_SCL/DIGIN[5] DRIVEOUT[0] STWBC-WA DRIVEOUT[3] VMAIN GPIO\_0 ISENSE GPIO\_1 NTC\_TEMP CPP\_INT\_3 SPARE\_ADC CPP\_INT\_0 RESERVED CPP\_REF RESERVED CPP\_INT\_1

Figure 3. STWBC-WA pin configuration

**Table 2. Pinout description** 

Pin number	Pin name	Pin type	Turnkey firmware description
1	UART_RX <sup>(1)</sup>	DI	UART RX link
2	PWM_AUX/GPIO_2 <sup>(1)</sup>	DO	Not used, must not be connected to any potential
3	I2C_SDA/DIGIN[4] <sup>(1)</sup>	-	Inactive (internal pull-up)
4	I2C_SCL/DIGIN[5] <sup>(1)</sup>	-	Inactive (internal pull-up)
5	DRIVEOUT[3] <sup>(1)</sup>	DO	Output driver for full-bridge configuration (optional)
6	GPIO_0 <sup>(1)</sup>	DO	Digital output for the green light indicator
7	GPIO_1 <sup>(1)</sup>	DO	Digital output for the red light indicator
8	CPP_INT_3	Al	Connected to GND
9	CPP_INT_2	Al	Connected to GND
10	CPP_REF	AI	External reference for CPP_INT_3 (if not used, must be tied to GND)
11	CPP_INT_1	Al	Connected to GND
12	CPP_INT_0	Al	WAVE_SNS signal for symbol detection
13	VDDA	PS	Analog power supply

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**Table 2. Pinout description (continued)** 

Pin number	Pin name	Pin type	Turnkey firmware description
14	VSSA	PS	Analog ground
15	RESERVED	Al	Reserved
16	RESERVED	-	Reserved
17	SPARE_ADC <sup>(1)</sup>	-	Connected to the USB_ID signal
18	NTC_TEMP	Al	NTC temperature measurement
19	ISENSE	Al	LC tank current measurement
20	VMAIN	Al	Vmain monitor
21	DRIVEOUT[0]	DO	Output driver for the low-side branch
22	DIGIN[0] <sup>(1)</sup>	-	Inactive (internal pull-up)
23	DIGIN[1] <sup>(1)</sup>	-	Inactive (internal pull-up)
24	DRIVEOUT[1]	DO	Output driver for the high-side branch
25	DRIVEOUT[2]	DO	Output driver for full-bridge configuration (optional)
26	DIGIN[2] <sup>(1)</sup>	-	Not connected
27	SWIM	DIO	Debug interface
28	NRST	DI	Reset
29	VDD	PS	Digital and I/O power supply
30	VSS	PS	Digital and I/O ground
31	VOUT	Supply	Internal LDO output
32	UART_TX <sup>(1)</sup>	DO	UART TX link

<sup>1.</sup> API configurable.

Note: All analog inputs are VDD compliant but can be used only between 0 and 1.2 V.



## 4 Electrical characteristics

### 4.1 Parameter conditions

Unless otherwise specified, all voltages are referred to  $V_{SS}$ .  $V_{DDA}$  and  $V_{DD}$  must be connected to the same voltage value.  $V_{SS}$  and  $V_{SSA}$  must be connected together with the shortest wire loop.

#### 4.1.1 Minimum and maximum values

Unless otherwise specified, the minimum and maximum values are guaranteed in the worst conditions of the ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at  $T_A = 25$  °C and  $T_A = T_A$  max. (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in *Table 3*, *Table 4* and in the footnotes of *Table 6 on page 12* to *Table 18 on page 24*, and are not tested in production.

### 4.1.2 Typical values

Unless otherwise specified, typical data are based on  $T_A = 25$  °C,  $V_{DD}$  and  $V_{DDA} = 3.3$  V. They are given only as design guidelines and are not tested. Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range.

## 4.1.3 Typical curves

Unless otherwise specified, all typical curves are given as design guidelines only and are not tested.

## 4.1.4 Typical current consumption

For typical current consumption measurements,  $V_{DD}$  and  $V_{DDA}$  are connected together as shown in *Figure 4*.



5 V or 3.3 V

VDDIO
VDDIA

GNDIO
GNDA

GIPD090520131534FSR

Figure 4. Supply current measurement conditions

## 4.1.5 Loading capacitors

The loading conditions used for the pin parameter measurement are shown in *Figure 5*:

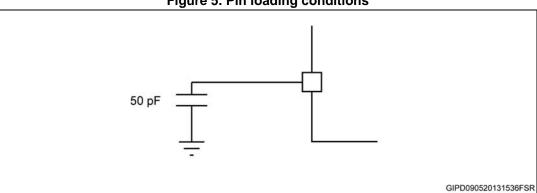
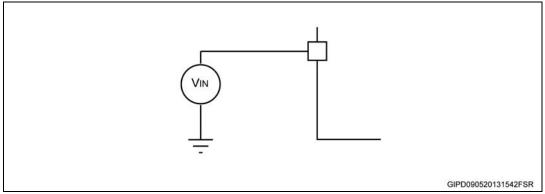


Figure 5. Pin loading conditions

## 4.1.6 Pin output voltage

The input voltage measurement on a pin is described in Figure 6.





## 4.2 Absolute maximum ratings

Stresses above those listed as "absolute maximum ratings" may cause permanent damage to the device. This is a stress rating only and the functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 3. Voltage characteristics

Symbol	Ratings	Min.	Max.	Unit	
V <sub>DDX</sub> - V <sub>SSX</sub>	Supply voltage <sup>(1)</sup>	-0.3	6.5	V	
V <sub>IN</sub>	Input voltage on any other pin <sup>(2)</sup>	VSS -0.3	VDD +0.3	V	
V <sub>DD</sub> - V <sub>DDA</sub>	Variation between different power pins	-	50	mV	
V <sub>SS</sub> - V <sub>SSA</sub>	Variation between all the different ground pins <sup>(3)</sup>	-	50	IIIV	
V <sub>ESD</sub>	Electrostatic discharge voltage	Refer to absolute maximum rati (electrical sensitivity) in Section 4.4.1 on page 26.			

<sup>1.</sup> All power  $V_{DDX}$  ( $V_{DD}$ ,  $V_{DDA}$ ) and ground  $V_{SSX}$  ( $V_{SS}$ ,  $V_{SSA}$ ) pins must always be connected to the external power supply.

3.  $V_{SS}$  and  $V_{SSA}$  signals must be interconnected together with a short wire loop.

I<sub>INJ(PIN)</sub> must never be exceeded. This is implicitly insured if V<sub>IN</sub> maximum is respected. If V<sub>IN</sub> maximum cannot be respected, the injection current must be limited externally to the I<sub>INJ(PIN)</sub> value. A positive injection is induced by V<sub>IN</sub> < V<sub>SS</sub>.

Tuble 4. Out the order of the o						
Symbol	Ratings	Max. <sup>(1)</sup>	Unit			
I <sub>VDDX</sub>	Total current into VDDX power lines <sup>(2)</sup>	100				
I <sub>VSSX</sub>	Total current out of VSSX power lines <sup>(2)</sup>	100				
I <sub>IO</sub>	Output current sunk by any I/Os and control pin	Ref. to Table 12 on page 16	mA			
	Output current source by any I/Os and control pin	-				
I <sub>INJ(PIN)</sub> <sup>(3)</sup> , <sup>(4)</sup>	Injected current on any pin	±4				
I <sub>INJ(TOT)</sub> <sup>(3)</sup> , <sup>(4)</sup> , <sup>(5)</sup>	Sum of injected currents	±20				

**Table 4. Current characteristics** 

- 1. Data based on characterization results, not tested in production
- 2. All power  $V_{DDX}$  ( $V_{DD}$ ,  $V_{DDA}$ ) and ground  $V_{SSX}$  ( $V_{SS}$ ,  $V_{SSA}$ ) pins must always be connected to the external power supply.
- 3. The  $I_{INJ(PIN)}$  must never be exceeded. This is implicitly insured if the  $V_{IN}$  maximum is respected. If the  $V_{IN}$  maximum cannot be respected, the injection current must be limited externally to the  $I_{INJ(PIN)}$  value. A positive injection is induced by  $V_{IN} > V_{DD}$  while a negative injection is induced by  $V_{IN} < V_{SS}$ .
- 4. The negative injection disturbs the analog performance of the device.
- 5. When several inputs are submitted to a current injection, the maximum  $\Sigma_{\text{IINJ}(\text{PIN})}$  is the absolute sum of the positive and negative injected currents (instantaneous values). These results are based on characterization with the  $\Sigma_{\text{IINJ}(\text{PIN})}$  maximum current injection on four I/O port pins of the device.

Table 5. Thermal characteristics

Symbol	Ratings	Max.	Unit
T <sub>STG</sub>	Storage temperature range	-65 to 150	°C
T <sub>J</sub>	Maximum junction temperature	150	°C



## 4.3 Operating conditions

The device must be used in operating conditions that respect the parameters in *Table 6*. In addition, a full account must be taken for all physical capacitor characteristics and tolerances.

Table 6. General operating conditions

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
V <sub>DD1</sub> , V <sub>DDA1</sub>	Operating voltages	-	3 <sup>(1)</sup>	-	5.5 <sup>(1)</sup>	
V <sub>DD</sub> , V <sub>DDA</sub>	Nominal operating voltages	-	3.3 <sup>(1)</sup>	-	5 <sup>(1)</sup>	V
V <sub>оит</sub>	Core digital power supply	-	-	1.8 <sup>(2)</sup>	-	
	C <sub>VOUT</sub> : capacitance of external capacitor <sup>(3)</sup>		470	-	3300	nF
	ESR of external capacitor <sup>(2)</sup>	at 1 MHz	0.05	-	0.2	Ω
	ESL of external capacitor <sup>(2)</sup>		-	-	-	-
Θ <sub>JA</sub> <sup>(4)</sup>	FR4 multilayer PCB	VFQFPN32	1	26	-	°C/W
T <sub>A</sub>	Ambient temperature	Pd = 100 mW	-40	-	105	°C

- 1. The external power supply can be within the range from 3 V up to 5.5 V.
- 2. Internal core power supply voltage.
- 3. Care should be taken when the capacitor is selected due to its tolerance, dependency on temperature, DC bias and frequency.
- 4. To calculate  $P_{Dmax}$  (T<sub>A</sub>), use the formula  $P_{Dmax}$  = (T<sub>Jmax</sub> T<sub>A</sub>)/ $\Theta_{JA}$ .

Table 7. Operating conditions at power-up/power-down

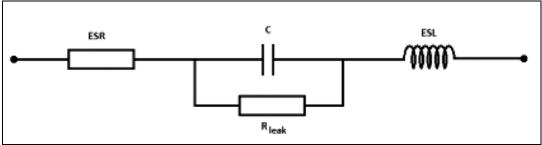
Symbol	Parameter	Conditions	Min. <sup>(1)</sup>	Тур.	Max. <sup>(2)</sup>	Unit
t <sub>TEMP</sub>	Reset release delay	V <sub>DD</sub> rising	-	3	-	ms
V <sub>IT</sub> +	Power-on reset threshold	-	2.65	2.8	2.98	V
V <sub>IT</sub> -	Brownout reset threshold	-	2.58	2.73	2.88	V

- 1. Guaranteed by design, not tested in production.
- 2. The power supply ramp must be monotone.

## 4.3.1 VOUT external capacitor

The stabilization of the main regulator is achieved by connecting an external capacitor  $C_{VOUT}^{(a)}$  to the VOUT pin. The  $C_{VOUT}$  is specified in *Section 4.3: Operating conditions*. Care should be taken to limit the series inductance to less than 15 nH.

Figure 7. External capacitor C<sub>VOUT</sub>



## 4.3.2 Internal clock sources and timing characteristics

#### **HSI RC oscillator**

The HSI RC oscillator parameters are specified under general operating conditions for  $V_{DD}$  and  $T_{A}$ .

Table 6: Hor No Coomator							
Symbol	Parameter	Conditions	Min. <sup>(1)</sup>	Тур.	Max. <sup>(1)</sup>	Unit	
f <sub>HSI</sub>	Frequency	-	-	16	-	MHz	
ACC <sub>HSI</sub>	Accuracy of the HSI oscillator (factory calibrated) <sup>(1)</sup> , <sup>(2)</sup>	$V_{DD} = 3.3 \text{ V}$ $T_{A} = 25  {}^{\circ}\text{C}$	-1%	-	+1%		
		$V_{DD} = 3.3 \text{ V}$ -40 °C ≤ $T_A \le 105 \text{ °C}$	-4%	-	+4%	%	
		$V_{DD} = 5 V$ -40 °C ≤ $T_A \le 105$ °C	-4%	-	+4%		
t <sub>SU(HSI)</sub>	HSI oscillator wakeup time including calibration	-	-	1	-	μs	

Table 8. HSI RC oscillator

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<sup>1.</sup> Data based on characterization results, not tested in production.

<sup>2.</sup> Variation referred to  $f_{\mbox{\scriptsize HSI}}$  nominal value.

a. ESR is the equivalent series resistance and ESL is the equivalent inductance.

### LSI RC oscillator

The LSI RC oscillator parameters are specified under general operating conditions for  $V_{DD}$  and  $T_{A}$ .

Table 9. LSI RC oscillator

Symbol	Parameter	Conditions	Min. <sup>(1)</sup>	Тур.	Max. <sup>(1)</sup>	Unit
f <sub>LSI</sub>	Frequency	-	-	153.6	-	kHz
ACC <sub>LSI</sub>	Accuracy of LSI oscillator	$3.3 \text{ V} \le \text{V}_{DD} \le 5 \text{ V}$ -40 °C $\le \text{T}_{A} \le 105 \text{ °C}$	-10%	ı	10%	%
t <sub>SU(LSI)</sub>	LSI oscillator wakeup time	-	-	7	-	μs

<sup>1.</sup> Guaranteed by design, not tested in production.

### **PLL** internal source clock

Table 10. PLL internal source clock

Symbol	Parameter	Conditions	Min	Тур.	Max. <sup>(1)</sup>	Unit
f <sub>IN</sub>	Input frequency <sup>(2)</sup>	0.01/ 11/ 151/	-	16	-	MHz
f <sub>OUT</sub>	Output frequency	$3.3 \text{ V} \le \text{V}_{DD} \le 5 \text{ V}$ -40 °C \le T_A \le 105 °C	-	96	-	IVII IZ
t <sub>lock</sub>	PLL lock time		1	ı	200	μs

<sup>1.</sup> Data based on characterization results, not tested in production.

<sup>2.</sup> PLL maximum input frequency 16 MHz.

## 4.3.3 Memory characteristics

## Flash program and memory/data EEPROM memory

General conditions:  $T_A = -40 \, ^{\circ}\text{C}$  to 105  $^{\circ}\text{C}$ .

Table 11. Flash program memory/data EEPROM memory

Symbol	Parameter	Conditions	Min. <sup>(1)</sup>	Typ. <sup>(1)</sup>	Max. <sup>(1)</sup>	Unit
t <sub>PROG</sub>	Standard programming time (including erase) for the byte/word/block (1 byte/4 bytes/128 bytes)	-	-	6	6.6	ms
	Fast programming time for 1 block (128 bytes)	-	-	3	3.3	ms
t <sub>ERASE</sub>	Erase time for 1 block (128 bytes)	-	-	3	3.3	ms
	Erase/write cycles <sup>(2)</sup> (program memory)	T <sub>A</sub> = 25 °C	10 K	-	-	
N <sub>WE</sub>	Erase/write cycles <sup>(2)</sup> (data memory)	T <sub>A</sub> = 85 °C	100 K	-	-	Cycles
	Erase/write cycles (data memory)	T <sub>A</sub> = 105 °C	35 K	-	-	
	Data retention (program memory) after 10 K erase/write cycles at T <sub>A</sub> = 25 °C	T <sub>RET</sub> = 85 °C	15	-	-	
	Data retention (program memory) after 10 K erase/write cycles at T <sub>A</sub> = 25 °C	T <sub>RET</sub> = 105 °C	11	-	-	Years
t <sub>RET</sub>	Data retention (data memory) after 100 K erase/write cycles at T <sub>A</sub> = 85 °C	T <sub>RET</sub> = 85 °C	15	-	-	Teals
	Data retention (data memory) after 35 K erase/write cycles at T <sub>A</sub> = 105 °C	T <sub>RET</sub> = 105 °C	6	-	-	
I <sub>DDPRG</sub>	Supply current during program and erase cycles	$-40  ^{\circ}\text{C} \le T_{A} \le 105  ^{\circ}\text{C}$		2	-	mA

<sup>1.</sup> Data based on characterization results, not tested in production.

<sup>2.</sup> The physical granularity of the memory is 4 bytes, so cycling is performed on 4 bytes even when a write/erase operation addresses a single byte.

## 4.3.4 I/O port pin characteristics

The I/O port pin parameters are specified under general operating conditions for  $V_{DD}$  and  $T_A$  unless otherwise specified. Unused input pins should not be left floating.

Table 12. Voltage DC characteristics

Symbol	Description	Min. <sup>(1)</sup>	Тур.	Max. <sup>(1)</sup>	Unit
V <sub>IL</sub>	Input low voltage	-0.3	-	0.3 * V <sub>DD</sub>	
V <sub>IH</sub>	Input high voltage <sup>(2)</sup>	0.7 * V <sub>DD</sub>	-	$V_{DD}$	
V <sub>OL1</sub>	Output low voltage at 3.3 V <sup>(3)</sup>	-	-	0.4 <sup>(4)</sup>	
V <sub>OL2</sub>	Output low voltage at 5 V <sup>(3)</sup>	-	-	0.5	
V <sub>OL3</sub>	Output low voltage high sink at 3.3 V / 5 V <sup>(2)</sup> , <sup>(5)</sup> , <sup>(6)</sup>	-	0.6 <sup>(4)</sup>	-	V
V <sub>OH1</sub>	Output high voltage at 3.3 V <sup>(3)</sup>	V <sub>DD</sub> - 0.4 <sup>(4)</sup>	-	-	
V <sub>OH2</sub>	Output high voltage at 5 V <sup>(3)</sup>	V <sub>DD</sub> - 0.5	-	-	
V <sub>OH3</sub>	Output high voltage high sink at 3.3 V / 5 V <sup>(2)</sup> , <sup>(5)</sup> , <sup>(6)</sup>	V <sub>DD</sub> - 0.6 <sup>(4)</sup>	-	-	
H <sub>VS</sub>	Hysteresis input voltage <sup>(7)</sup>	0.1 * V <sub>DD</sub>	-	-	
R <sub>PU</sub>	Pull-up resistor	30	45	60	kΩ

<sup>1.</sup> Data based on characterization result, not tested in production.

<sup>2.</sup> All signals are not 5 V tolerant (input signals cannot exceed  $V_{DDX}$  ( $V_{DDX} = V_{DD}$ ,  $V_{DDA}$ ).

<sup>3.</sup> Parameter applicable to signals: GPIO\_[0:2], DRIVEOUT[0:3], PWM\_AUX.

<sup>4.</sup> Electrical threshold voltage not yet characterized at -40 °C.

<sup>5.</sup> The parameter applicable to the signal: SWIM.

<sup>6.</sup> The parameter applicable to the signal: DIGIN [0].

<sup>7.</sup> Applicable to any digital inputs.

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**Table 13. Current DC characteristics** 

Symbol	Description	Min.	Тур.	Max. <sup>(1)</sup>	Unit
I <sub>OL1</sub>	Standard output low level current at 3.3 V and V <sub>OL1</sub> <sup>(2)</sup>	-	-	1.5	
I <sub>OL2</sub>	Standard output low level current at 5 V and V <sub>OL 2</sub> <sup>(2)</sup>	-	-	3	
I <sub>OLhs1</sub>	High sink output low level current at 3.3 V and V <sub>OL3</sub> <sup>(3)</sup> , <sup>(4)</sup>	-	-	5	
I <sub>OLhs2</sub>	High sink output low level current at 5 V and V <sub>OL</sub> <sup>(3)</sup> , <sup>(4)</sup>	-	-	7.75	mA
I <sub>OH1</sub>	Standard output high level current at 3.3 V and V <sub>OH1</sub> <sup>(2)</sup>	-	-	1.5	ША
I <sub>OH2</sub>	Standard output high level current at 5 V and V <sub>OLH2</sub> <sup>(2)</sup>	-	-	3	
I <sub>OHhs1</sub>	High sink output low level current at 3.3 V and V <sub>OH3</sub> <sup>(3)</sup> , <sup>(4)</sup>	-	-	5	
I <sub>OHhs2</sub>	High sink output low level current at 5 V and V <sub>OH3</sub> <sup>(3)</sup> , <sup>(4)</sup>	-	-	7.75	
I <sub>LKg</sub>	Input leakage current digital - analog $V_{SS} \le V_{IN} \ge V_{DD}^{(5)}$	-	-	± 1	μΑ
I_ <sub>lnj</sub>	Injection current <sup>(6)</sup> , <sup>(7)</sup>	-	-	±4	mA
$\Sigma I_{-Inj}$	Total injection current (sum of all I/O and control pins) <sup>(6)</sup>	-	-	± 20	IIIA

- 1. Data based on characterization result, not tested in production.
- 2. The parameter applicable to signals:  $\mathsf{GPIO}[0:2]$ ,  $\mathsf{DRIVEOUT}[0:3]$ ,  $\mathsf{PWM}\_\mathsf{AUX}$ .
- 3. The parameter applicable to the signal: SWIM.
- 4. The parameter applicable to the signal: DIGIN [0].
- 5. Applicable to any digital inputs.
- 6. The maximum value must never be exceeded.
- 7. The negative injection current on the ADCIN [7:0] signals (product depending) => SPARE\_ADC signals have to be avoided since they impact ADC conversion accuracy.

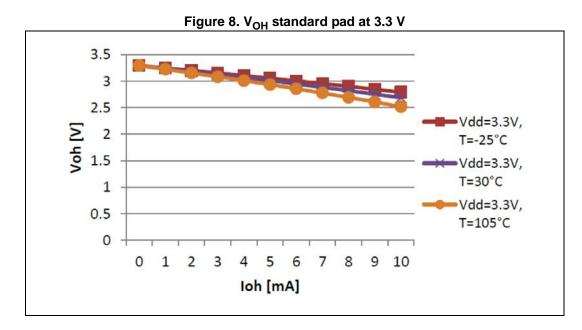


## 4.3.5 Typical output level curves

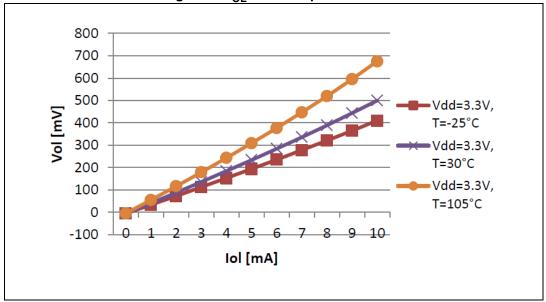
This section shows the typical output voltage level curves measured on a single output pin for the two-pad family present in the STWBC-WA device.

#### Standard pad

This pad is associated to the following signals: DIGIN [0:1], SWIM and GPIO\_[0:2] when available.







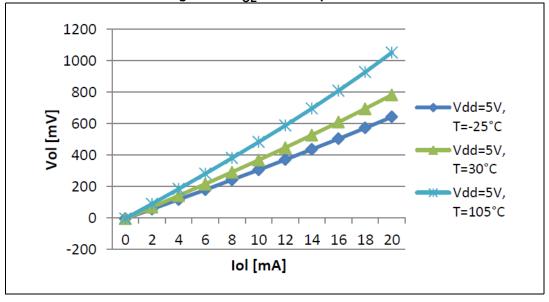
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6 5 4 Vdd=5V, T=-25°C 3 Vdd=5V, 2 T=30°C 1 Vdd=5V, T=105°C 0 10 12 14 16 18 20 Ioh [mA]

Figure 10. V<sub>OH</sub> standard pad at 5 V

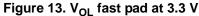


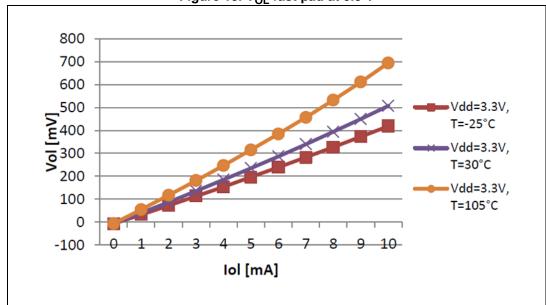


#### Fast pad 4.3.6

This pad is associated to the DRIVEOUT[0:3], PWM\_AUX signals if the external pin is available.

Figure 12. V<sub>OH</sub> fast pad at 3.3 V 3.5 3 2.5 Vdd=3.3V, ∑ 2 **yo** 1.5 T=-25°C Vdd=3.3V, T=30°C 1 Vdd=3.3V, 0.5 T=105°C 0 0 1 2 3 5 6 7 8 9 10 Ioh [mA]





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Figure 14. V<sub>OH</sub> fast pad at 5 V

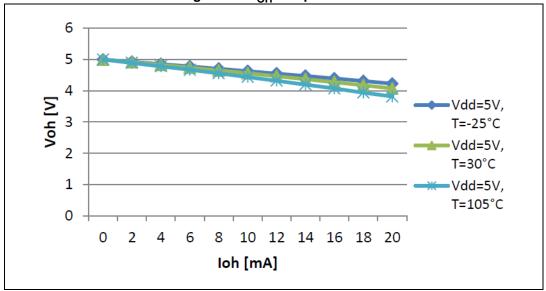
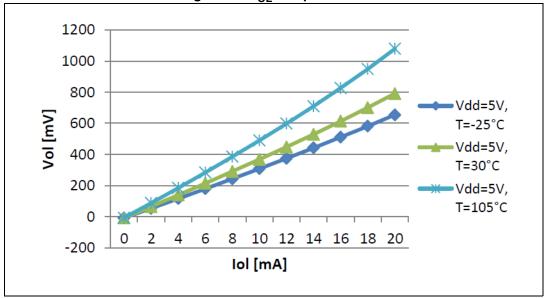


Figure 15. V<sub>OL</sub> fast pad at 5 V



## 4.3.7 Reset pin characteristics

The reset pin parameters are specified under general operating conditions for  $V_{DD}$  and  $T_{A}$  unless otherwise specified.

Table 14. NRST pin characteristics

Symbol	Parameter	Conditions	Min. <sup>(1)</sup>	Тур.	Max. <sup>(1)</sup>	Unit
V <sub>IL(NRST)</sub>	NRST input low level voltage <sup>(1)</sup>	-	-0.3	-	0.3 x V <sub>DD</sub>	
V <sub>IH(NRST)</sub>	NRST input high level voltage <sup>(1)</sup>	-	0.7 x V <sub>DD</sub>	-	V <sub>DD</sub> + 0.3	V
V <sub>OL(NRST)</sub>	NRST output low level voltage <sup>(1)</sup>	I <sub>OL</sub> = 2 mA	-	-	0.5	
R <sub>PU(NRST)</sub>	NRST pull-up resistor <sup>(2)</sup>	-	30	40	60	kΩ
t <sub>IFP(NRST)</sub>	NRST input filtered pulse <sup>(3)</sup>	-	-	-	75	ns
t <sub>INFP(NRST)</sub>	NRST not input filtered pulse <sup>(3)</sup>	-	500	-	-	119
t <sub>OP(NRST)</sub>	NRST output filtered pulse <sup>(3)</sup>	-	15	-	-	μs

<sup>1.</sup> Data based on characterization results, not tested in production.

## 4.3.8 I<sup>2</sup>C interface characteristics

Table 15. I<sup>2</sup>C interface characteristics

Complete	Parameter	Standard mode		Fast mode		Unit
Symbol	Parameter	Min. <sup>(1)</sup>	Max. <sup>(1)</sup>	Min. <sup>(1)</sup>	Max. <sup>(1)</sup>	Unit
t <sub>w(SCLL)</sub>	SCL clock low time	4.7	-	1.3	-	116
t <sub>w(SCLH)</sub>	SCL clock high time	4.0	-	0.6	-	μs
t <sub>su(SDA)</sub>	SDA setup time	250	-	100	-	
t <sub>h(SDA)</sub>	SDA data hold time	0 <sup>(2)</sup>	-	0 <sup>(2)</sup>	900 <sup>(2)</sup>	ns
t <sub>r(SDA)</sub> t <sub>r(SCL)</sub>	SDA and SCL rise time (VDD = 3.3 to 5 V) <sup>(3)</sup>	-	1000	-	300	115
t <sub>f(SDA)</sub> t <sub>f(SCL)</sub>	SDA and SCL fall time (VDD = $3.3 \text{ to } 5 \text{ V})^{(3)}$	-	300	-	300	
t <sub>h(STA)</sub>	START condition hold time	4.0	-	0.6	-	
t <sub>su(STA)</sub>	Repeated START condition setup time	4.7	-	0.6	-	μs
t <sub>su(STO)</sub>	STOP condition setup time	4.0	-	0.6	-	μs
t <sub>w(STO:STA)</sub>	STOP to START condition time (bus free)	4.7	-	1.3	-	μs
C <sub>b</sub>	Capacitive load for each bus line <sup>(4)</sup>	-	50	-	50	pF

<sup>1.</sup> Data based on the standard  $I^2C$  protocol requirement, not tested in production.

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<sup>2.</sup> The RPU pull-up equivalent resistor is based on a resistive transistor.

<sup>3.</sup> Data guaranteed by design, not tested in production.

<sup>2.</sup> The maximum hold time of the start condition need only be met if the interface does not stretch the low time.

<sup>3.</sup> I<sup>2</sup>C multifunction signals require the high sink pad configuration and the interconnection of 1 K pull-up resistances.

<sup>4.</sup> 50 pF is the maximum load capacitance value to meet the  $I^2C$  std. timing specifications.

#### 4.3.9 10-bit SAR ADC characteristics

The 10-bit SAR ADC oscillator parameters are specified under general operating conditions for  $V_{DDA}$  and  $T_A$  unless otherwise specified.

Table 16. ADC characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
N	Resolution	-	-	10	-	bit
R <sub>ADCIN</sub>	ADC input impedance	-	1	-	-	ΜΩ
V <sub>IN1</sub>	Conversion voltage range for the gain x1	-	0	-	1.25 <sup>(1)</sup> , <sup>(2)</sup>	V
V <sub>ref</sub>	ADC main reference voltage <sup>(3)</sup>	-	-	1.250	-	V

- 1. The maximum input analog voltage cannot exceed V<sub>DDA</sub>.
- Exceeding the maximum voltage on the SPARE\_ADC signals for the related conversion scale must be avoided since the ADC conversion accuracy can be impacted.
- 3. The ADC reference voltage at  $T_A$  = 25 °C.

## ADC accuracy characteristics at V<sub>DD</sub>/V<sub>DDA</sub> 3.3 V

Table 17. ADC accuracy characteristics at V<sub>DD</sub>/V<sub>DDA</sub> 3.3 V

Symbol	Parameter	Typ. <sup>(1)</sup>	Min. <sup>(2)</sup>	Max. <sup>(2)</sup>	Unit
E <sub>T</sub>	Total unadjusted error <sup>(3)</sup> , <sup>(4)</sup> , <sup>(5)</sup>	2.8	-	-	
E <sub>O</sub>	Offset error <sup>(3)</sup> , <sup>(4)</sup> , <sup>(5)</sup>	0.3	-	-	
E <sub>G</sub>	Gain error <sup>(3)</sup> , <sup>(4)</sup> , <sup>(5)</sup> , <sup>(6)</sup>	0.4	-	-	
E <sub>O+G</sub>	Offset + gain error <sup>(6)</sup> , <sup>(7)</sup>	-	-8.5	9.3	LSB
E <sub>O+G</sub>	Offset + gain error <sup>(6)</sup> , <sup>(8)</sup>	-	-11	11	LSB
E <sub>O+G</sub>	Offset + gain error <sup>(6)</sup> , <sup>(9)</sup>	-	-14.3	11.3	
E <sub>D</sub>	Differential linearity error <sup>(1)</sup> , (2), (3)	0.5	-	-	
E <sub>L</sub>	Integral linearity error <sup>(3)</sup> , <sup>(4)</sup> , <sup>(5)</sup>	1.4	-	-	

- 1. Temperature operating:  $T_A = 25$  °C.
- 2. Data based on characterization results, not tested in production.
- 3. ADC accuracy vs. the negative injection current. The injecting negative current on any of the analog input pins should be avoided as this reduces the accuracy of the conversion being performed on another analog input. It is recommended a Schottky diode (pin to ground) to be added to standard analog pins which may potentially inject the negative current. Any positive injection current within the limits specified for  $I_{\text{INJ}(P\text{IN})}$  and  $\Sigma_{\text{INJ}(P\text{IN})}$  in the I/O port pin characteristic section does not affect the ADC accuracy. The ADC accuracy parameters may be also impacted exceeding the ADC maximum input voltage  $V_{\text{IN1}}$  or  $V_{\text{IN2}}$ .
- 4. Results in the manufacturing test mode.
- 5. Data aligned with trimming voltage parameters.
- 6. Gain error evaluation with the two point method.
- 7. Temperature operating range: 0  ${}^{\circ}C \le T_A \le 85 {}^{\circ}C$ .
- 8. Temperature operating range: -25  $^{o}C \leq T_{A} \leq$  105  $^{o}C.$
- 9. Temperature operating range: -40  $^{o}C \leq T_{A} \leq 105 \ ^{o}C.$



## ADC accuracy characteristics at V<sub>DD</sub>/V<sub>DDA</sub> 5 V

Table 18. ADC accuracy characteristics at V<sub>DD</sub>/V<sub>DDA</sub> 5 V

Symbol	Parameter	Typ. <sup>(1)</sup>	Min. <sup>(2)</sup>	Max. <sup>(2)</sup>	Unit
E <sub>T</sub>	Total unadjusted error <sup>(3)</sup> (4), (5)	TBD	-	-	
E <sub>O</sub>	Offset error <sup>(3)</sup> , <sup>(4)</sup> , <sup>(5)</sup>	0.5	-	-	
E <sub>G</sub>	Gain error <sup>(3)</sup> , <sup>(4)</sup> , <sup>(5)</sup> , <sup>(6)</sup>	0.4	-	-	
E <sub>O+G</sub>	Offset + gain error <sup>(6)</sup> , <sup>(7)</sup>	-	-8.3	8.9	LSB
E <sub>O+G</sub>	Offset + gain error <sup>(6)</sup> , <sup>(8)</sup>	-	-10.9	10.9	LOD
EO+G	Offset + gain error <sup>(6)</sup> , <sup>(9)</sup>	-	-13.8	10.9	
E <sub>D</sub>	Differential linearity error <sup>(1)</sup> , <sup>(2)</sup> , <sup>(3)</sup>	0.8	-	-	
E <sub>L</sub>	Integral linearity error <sup>(3)</sup> , <sup>(4)</sup> , <sup>(5)</sup>	2.0	-	-	

- 1. Operating temperature:  $T_A = 25$  °C.
- 2. Data based on characterization results, not tested in production.
- 3. ADC accuracy vs. the negative injection current. The injecting negative current on any of the analog input pins should be avoided as this reduces the accuracy of the conversion being performed on another analog input. It is recommended that a Schottky diode (pin to ground) be to added to standard analog pins which may potentially inject the negative current. Any positive injection current within the limits specified for I<sub>INJ(PIN)</sub> and Σ<sub>IINJ(PIN)</sub> in the I/O port pin characteristic section does not affect the ADC accuracy. The ADC accuracy parameters may be also impacted exceeding the ADC maximum input voltage V<sub>IN1</sub> or V<sub>IN2</sub>.
- 4. Results in the manufacturing test mode.
- 5. Data aligned with trimming voltage parameters.
- 6. Gain error evaluation with the two point method.
- 7. Operating temperature range: 0 °C  $\leq$  T<sub>A</sub>  $\leq$  85 °C.
- 8. Operating temperature range: -25  $^{\circ}$ C  $\leq$  T<sub>A</sub>  $\leq$  105  $^{\circ}$ C.
- 9. Operating temperature range: -40 °C  $\leq$  T<sub>A</sub>  $\leq$  105 °C.

### **ADC** conversion accuracy

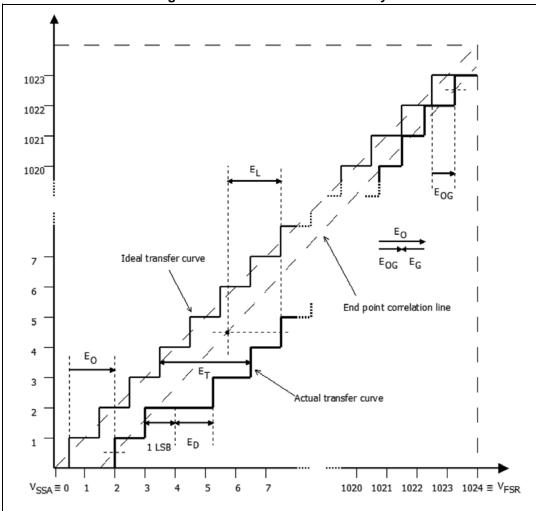


Figure 16. ADC conversion accuracy

### ADC accuracy parameter definitions:

- E<sub>T</sub> = total unadjusted error: the maximum deviation between the actual and the ideal transfer curves.
- **E<sub>O</sub>** = offset error: the deviation between the first actual transition and the first ideal one.
- **E**<sub>OG</sub> = offset + gain error (1-point gain): the deviation between the last ideal transition and the last actual one.
- **E**<sub>G</sub> = gain error (2-point gain): defined so that E<sub>OG</sub> = E<sub>O</sub> + E<sub>G</sub> (parameter correlated to the deviation of the characteristic slope).
- **E**<sub>D</sub> = differential linearity error: the maximum deviation between actual steps and the ideal one.
- **E**<sub>L</sub> = integral linearity error: the maximum deviation between any actual transition and the end point correlation line.



### 4.4 EMC characteristics

## 4.4.1 Electrostatic discharge (ESD)

Electrostatic discharges (3 positive and then 3 negative pulses separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts \* (n + 1) supply pin).

Maximum **Symbol Ratings Conditions** Unit value Electrostatic discharge voltage  $T_A = 25$  °C, conforming to 2000  $V_{ESD(HBM)}$ JEDEC/JESD22-A114E (human body model) Electrostatic discharge voltage  $T_A = 25$  °C, conforming to ٧ V<sub>ESD(CDM)</sub> 500 (charge device model) ANSI/ESD STM 5.3.1 ESDA

 $T_A = 25$  °C, conforming to

JEDEC/JESD-A115-A

200

Table 19. ESD absolute maximum ratings

Data based on characterization results, not tested in production.

Electrostatic discharge voltage

(machine model)

### 4.4.2 Static latch-up

V<sub>ESD(MM)</sub>

Two complementary static tests are required on 10 parts to assess the latch-up performance.

A supply overvoltage (applied to each power supply pin) and a current injection (applied to the each input, output and configurable I/O pin) are performed on each sample. This test conforms to the EIA/JESD 78 IC latch-up standard.

Table 20. Electrical sensitivity

Symbol	Parameter	Conditions	Level
LU	Static latch-up class	T <sub>A</sub> = 105 °C	А

## 5 Thermal characteristics

The STWBC-WA functionality cannot be guaranteed when the device, in operation, exceeds the maximum chip junction temperature  $(T_{Jmax})$ .

T<sub>Jmax</sub>, in °C, may be calculated using equation:

$$T_{Jmax} = T_{Amax} + (P_{Dmax} \times \Theta J_A)$$

where:

T<sub>Amax</sub> is the maximum ambient temperature in °C

 $\mathcal{O}\!J_{\mathcal{A}}$  is the package junction-to-ambient thermal resistance in °C/W

 $P_{Dmax}$  is the sum of  $P_{INTmax}$  and  $P_{I/Omax}$  ( $P_{Dmax} = P_{INTmax} + PI/O_{max}$ )

 $P_{INTmax}$  is the product of  $I_{DD}$  and  $V_{DD}$ , expressed in watts. This is the maximum chip internal power.

 $P_{I/Omax}$  represents the maximum power dissipation on output pins where:

$$P_{I/Omax} = \Sigma (V_{OL} * I_{OL}) + \Sigma [(V_{DD} - V_{OH}) * I_{OH}],$$

taking into account the actual V<sub>OL</sub>/I<sub>OL</sub> and V<sub>OH</sub>/I<sub>OH</sub> of the I/Os at the low and high level.

Table 21. Package thermal characteristics

Symbol	Parameter	Value	Unit
$\Theta_{JA}$	VFQFPN32 - thermal resistance junction to ambient <sup>(1)</sup>	26	°C/W

<sup>1.</sup> Thermal resistance is based on the JEDEC JESD51-2 with a 4-layer PCB in a natural convection environment

**Package information** STWBC-WA

#### **Package information** 6

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

#### **VFQFPN32** package information 6.1

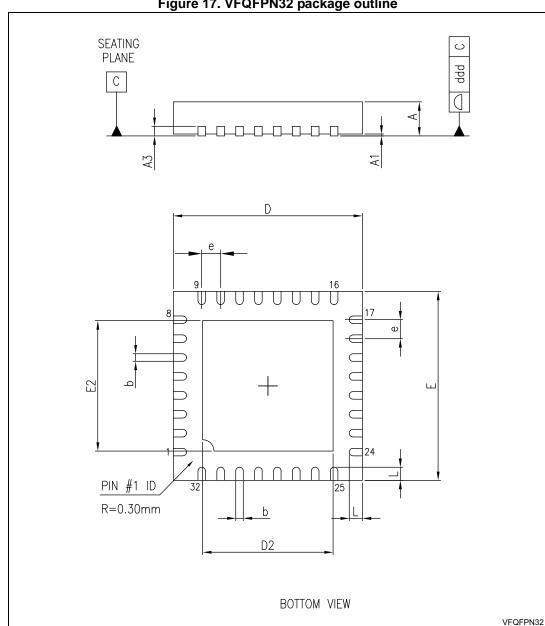


Figure 17. VFQFPN32 package outline

STWBC-WA Package information

Table 22. VFQFPN32 package mechanical data

Symbol	Dimensions (mm)				
Symbol	Min.	Тур.	Max.		
А	0.80	0.90	1.00		
A1	0	0.02	0.05		
A3	-	0.20	-		
b	0.18	0.25	0.30		
D	4.85	5.00	5.15		
D2	3.40	3.45	3.50		
E	4.85	5.00	5.15		
E2	3.40	3.45	3.50		
е	-	0.50	0.55		
L	0.30	0.40	0.50		
ddd	-	-	0.08		

#### Note:

- 1. VFQFPN stands for "Thermally Enhanced Very thin Fine pitch Quad Flat Package No lead".
- 2. Very thin profile:  $0.80 < A \le 1.00$  mm.
- 3. Pin 1 can be identified via a package mold or marking option on the top surface.
- 4. Package outline exclusive of any mold flash dimensions and metal burrs.

# 7 STWBC-WA development tools

The development tool for the STWBC-WA controller is provided by the IAR with the C compiler, which provides start-to-finish control of application development including code editing, compilation, optimization and debugging.

The hardware tool includes the ST-LINK/V2 in-circuit debugger/programmer (USB/SWIM).

## 8 Order codes

Table 23. Silicon product order codes

Order code	Package	Packaging
STWBC-WA	VFQFPN32	Tube
STWBC-WATR	VI QI FNOZ	Tape and reel

# 9 Revision history

Table 24. Document revision history

Date	Revision	Changes
30-Aug-2016	1	Initial release.

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